



BSI Standards Publication

Semiconductor devices — Non-destructive recognition criteria of defects in silicon carbide homoepitaxial wafer for power devices

Part 4: Procedure for identifying and evaluating defects using a combined method of optical inspection and photoluminescence

National foreword

This British Standard is the UK implementation of IEC 63068-4:2022.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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Published by BSI Standards Limited 2022

ISBN 978 0 539 18417 4

ICS 31.080.99

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 30 September 2022.

Amendments/corrigenda issued since publication

Date	Text affected
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